# EMC TEST REPORT For

### **TEA-Energy China Limited**

T8 LED Tube

Model No.: T8-25W-150-ND-W-T00

Additional Model No: Please Refer To Page 58

Prepared for : TEA-Energy China Limited

Address : 0100029 Building, Xiawei Industrial Zone, Xiahu

Community, Guanlan Town, Longhua District, Shenzhen,

China

Prepared by

Shenzhen LCS Compliance Testing Laboratory Ltd.

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Mail : webmaster@LCS-cert.com

Date of receipt of test sample : February 25, 2014

Number of tested samples : 1

Serial number : Prototype

Date of Test : February 25, 2014 - March 04, 2014

Date of Report : March 04, 2014



#### EMC TEST REPORT

EN 55015: 2006+A1: 2007+A2: 2009

Limits and methods of measurement of radio disturbance characteristics of electrical lighting and similar equipment

EN 61547: 2009

Equipment for general lighting purposes - EMC immunity requirements

Report Reference No. .....: LCS140225048E

Date Of Issue .....: March 04, 2014

Testing Laboratory Name .....: Shenzhen LCS Compliance Testing Laboratory Ltd.

Address .....: 1/F., Xingyuan Industrial Park, Tongda Road, Bao'an Avenue,

Bao'an District, Shenzhen, Guangdong, China

Testing Location/ Procedure.....: Full application of Harmonised standards

Partial application of Harmonised standards

Other standard testing method

Applicant's Name .....: TEA-Energy China Limited

Address .....: 0100029 Building, Xiawei Industrial Zone, Xiahu Community,

Guanlan Town, Longhua District, Shenzhen, China

**Test Specification:** 

Standard : EN 55015: 2006+A1: 2007+A2: 2009

EN 61000-3-2: 2006+A1: 2009+A2: 2009

EN 61000-3-3: 2008 EN 61547: 2009

Test Report Form No.....: LCSEMC-1.0

TRF Originator .....: Shenzhen LCS Compliance Testing Laboratory Ltd.

Master TRF....: Dated 2011-03

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Test Item Description. .....: T8 LED Tube

Trade Mark .....: QALEDO

Model/ Type Reference ...... T8-25W-150-ND-W-T00

Ratings.....: 100-240V~, 50/60Hz, Max.25W

Result .....: Positive

Compiled by:

**Supervised by:** 

Approved by:

York World

Fox Zhang/ Technique principal

Gavin Liang/ Manager

Yoyo Wang/ File administrators

# **EMC -- TEST REPORT**

Test Report No.: LCS140225048E

March 04, 2014

Date of issue

Type / Model	: T8-25W-150-ND-W-T00
EUT	: T8 LED Tube
Applicant	: TEA-Energy China Limited
Address	: 0100029 Building, Xiawei Industrial Zone, Xiahu
	Community, Guanlan Town, Longhua District, Shenzhen, China
Telephone	: /
Fax	: /
Manufacturer	: TEA-Energy China Limited
Address	: 0100029 Building, Xiawei Industrial Zone, Xiahu Community, Guanlan Town, Longhua District, Shenzhen, China
Telephone	: /
Fax	: /
Factory	: TEA-Energy China Limited
Address	: 0100029 Building, Xiawei Industrial Zone, Xiahu Community, Guanlan Town, Longhua District, Shenzhen,
	China
Telephone	
Fax	: /

**Test Result** according to the standards on page 7: **Positive** 

The test report merely corresponds to the test sample.

It is not permitted to copy extracts of these test result without the written permission of the test laboratory.

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# 1. SUMMARY OF STANDARDS AND RESULTS

# 1.1.Description of Standards and Results

The EUT have been tested according to the applicable standards as referenced below.

EMISSION (EN 55015: 2006+A1: 2007+A2: 2009)						
Description of Test Item		Standard		Limits	Results	
Conducted disturbance at mains terminals	E	N 55015: 2006+A1: 2007+A2: 200	09		PASS	
Magnetic field emission	E	N 55015: 2006+A1: 2007+A2: 200	09		PASS	
Radiated disturbance	Е	N 55015: 2006+A1: 2007+A2: 200	09		PASS	
Harmonic current emissions	EN	61000-3-2: 2006+A1: 2009+A2: 2	2009	Class C	PASS	
Voltage fluctuations & flicker EN 61000-3-3: 2008					PASS	
	IMMUNITY (EN 61547: 2009)					
Description of Test Item		Basic Standard	Performance Criteria		Results	
Electrostatic discharge (ESD)		EN 61000-4-2: 2009		В	PASS	
Radio-frequency, Continuous radiated disturbance		EN 61000-4-3: 2006+A1: 2008		Α	PASS	
Electrical fast transient (EFT)		EN 61000-4-4: 2004+A1: 2010		В	PASS	
Surge (Input a.c. power ports)		EN 61000-4-5: 2006		В	PASS	
Radio-frequency, Continuous conducted disturband	е	EN 61000-4-6: 2009		Α	PASS	
Power frequency magnetic field		EN 61000-4-8: 2010		Α	PASS	
Voltage dips, 30% reduction		EN 61000-4-11: 2004		С	PASS	
Voltage interruptions		EN 01000-4-11. 2004		В	PASS	
N/A is an abbreviation for Not Ap	plica	able.				

### 1.2.Description of Performance Criteria

#### **General Performance Criteria**

Examples of functions defined by the manufacturer to be evaluated during testing include, but are not limited to, the following:

- essential operational modes and states;
- tests of all peripheral access (hard disks, floppy disks, printers, keyboard, mouse, etc.);
- quality of software execution;
- quality of data display and transmission;
- quality of speech transmission.

#### 1.2.1.Performance criterion A

The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacture when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be deriver from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

### 1.2.2.Performance criterion B

After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacture, when the equipment is used as intended. The performance level may be replaced by a permissible loss of performance.

During the test, degradation of performance is allowed. However, no change of operation state or stored data is allowed to persist after the test.

If the minimum performance level (or the permissible performance loss) is not specified by the manufacturer, then either of these may be deriver from the product description and documentation, and by what the user may reasonably expect from the equipment if used as intended.

#### 1.2.3.Performance criterion C

Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacture's instructions.

Functions, and/or information stored in non-volatile memory, or protected by a battery backup, shall not be loss.

### 2. GENERAL INFORMATION

2.1.Description of Device (EUT)

EUT : T8 LED Tube

Model Number : T8-25W-150-ND-W-T00

Power Supply : 100-240V~, 50/60Hz, Max.25W

### 2.2.Description of Test Facility

Site Description

EMC Lab. : Accredited by CNAS, April 28, 2013

The Certificate Registration Number. is L4595.

Accredited by FCC, July 14, 2011

The Certificate Registration Number. is 899208.

Accredited by Industry Canada, May. 02, 2011 The Certificate Registration Number. is 9642A-1

Accredited by VCCI, Japan January 30, 2012

The Certificate Registration Number. is C-4260 and R-3804

Accredited by ESMD, April 24, 2012

The Certificate Registration Number. is ARCB0108.

Accredited by UL, July 25, 2013

The Certificate Registration Number. is 100571-492.

Accredited by TUV, December 23, 2013

The Certificate Registration Number. is SCN1134

Accredited by Intertek, October 30, 2013

The Certificate Registration Number. is 2011-RTL-L1-50.

### 2.3. Statement of the measurement uncertainty

The data and results referenced in this document are true and accurate. The reader is cautioned that there may be errors within the calibration limits of the equipment and facilities. The measurement uncertainty was calculated for all measurements listed in this test report acc. To CISPR 16 – 4 "Specification for radio disturbance and immunity measuring apparatus and methods – Part 4: Uncertainty in EMC Measurements" and is documented in the LCS quality system acc. To DIN EN ISO/IEC 17025. Furthermore, component and process variability of devices similar to that tested may result in additional deviation. The manufacturer has the sole responsibility of continued compliance of the device.

# 2.4. Measurement Uncertainty

Test Item	Frequency Range		Uncertainty	Note
Radiation Uncertainty		30MHz~200MHz	±2.96dB	(1)
	•	200MHz~1000MHz ±3.10dB		(1)
Conduction Uncertainty: 1		150kHz~30MHz	±1.63dB	(1)
Power disturbance		30MHz~300MHz	±1.60dB	(1)

(1). This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

# 3. MEASURING DEVICES AND TEST EQUIPMENT

### 3.1.Conducted Disturbance

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	EMI Test Receiver	ROHDE & SCHWARZ	ESCI	101142	2013/06/18
2	<b>EMI Test Receiver</b>	ROHDE & SCHWARZ	ESPI	101840	2013/06/18
3	Artificial Mains	ROHDE & SCHWARZ	ENV216	101288	2013/06/18
4	EMI Test Software	AUDIX	E3	N/A	2013/06/18

Report No.: LCS140225048E

### 3.2.Disturbance Power

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	<b>EMI Test Receiver</b>	ROHDE & SCHWARZ	ESCI	101142	2013/06/18
2	<b>EMI Test Receiver</b>	ROHDE & SCHWARZ	ESPI	101840	2013/06/18
3	Absorbing clamp	ROHDE & SCHWARZ	MDS 21	4033	2013/06/19
4	EMI Test Software	AUDIX	E3	N/A	2013/06/18

# 3.3.Radiated Electromagnetic Disturbance

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	EMI Test Receiver	ROHDE & SCHWARZ	ESCI	101142	2013/06/18
2	Triple-loop Antenna	EVERFINE	LLA-2	11050003	2013/06/18
3	EMI Test Receiver	ROHDE & SCHWARZ	ESPI	101840	2013/06/18
4	EMI Test Software	AUDIX	E3	N/A	2013/06/18

# 3.4. Radiated Disturbance (Electric Field)

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	EMI Test Receiver	ROHDE & SCHWARZ	ESCI	101142	2013/06/18
2	EMI Test Receiver	ROHDE & SCHWARZ	ESPI	101840	2013/06/18
3	Log per Antenna	SCHWARZBECK	VULB9163	9163-470	2013/06/21
4	Amplifier	Compliance Direction	PAP-0102	21001	2013/06/18
5	Spectrum Analyzer	Agilent	E4407B	MY41440754	2013/07/16
6	Horn Antenna	ETS.LINDGREN	3115	00034771	2013/12/11
7	EMI Test Software	AUDIX	E3	N/A	2013/06/18

### 3.5. Harmonic Current

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Power Analyzer Test System	Voltech	PM6000	20000670053	2013/06/18

# 3.6. Voltage fluctuation and Flicker

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Power Analyzer Test System	Voltech	PM6000	20000670053	2013/06/18

# 3.7. Electrostatic Discharge

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	ESD Simulator	KIKUSUI	KC001311	KES4021	2013/06/19

# 3.8.RF Field Strength Susceptibility

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	SIGNAL GENERATOR	HP	8648A	625U00573	2013/06/17
2	Amplifier	AR	500A100	17034	2013/06/18
3	Amplifier	AR	100W/1000M	17028	2013/06/18
3	Ampinici	AK	1	17028	
4	Isotropic Field Monitor	AR	FM2000	16829	2013/06/18
5	Isotropic Field Probe	AR	FP2000	16755	2013/06/18
6	Bi-conic Antenna	EMCO	3108	9507-2534	2013/06/19
7	By-log-periodic Antenna	AR	AT1080	16812	2013/06/19
8	EMS Test Software	ROHDE & SCHWARZ	ESK1	N/A	2013/06/19

# 3.9. Electrical Fast Transient/Burst

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Electrical fast transient(EFT)generator	3CTEST	EFT-4021	EC0461044	2013/06/18
2	Coupling Clamp	3CTEST	EFTC	EC0441098	2013/06/18

# 3.10.Surge

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Surge test system	3CTEST	SG-5006G	EC5581070	2013/06/18
2	Coupling/decoupling network	3CTEST	SGN-5010G	ECS5591033	2013/06/18

# 3.11.Conducted Susceptibility

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Conducted Immunity Test System	FRANKONIA	CIT-10	126A1195	2013/06/18
2	Coupling/decoupling network	FRANKONIA	CDN-M2+M3	A2210177	2013/06/18

# 3.12. Power Frequency Magnetic Field Susceptibility

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Power frequency mag-field generator System	EVERFINE	EMS61000-8 K	906003	2013/06/18

# 3.13. Voltage Dips

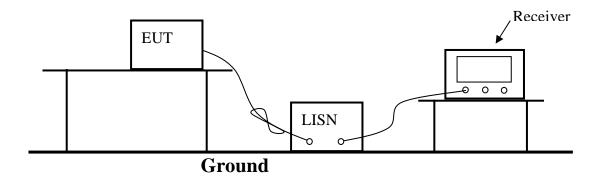
Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Voltage dips and up generator	3CTEST	VDG-1105G	EC0171014	2013/06/18

# 3.14. Voltage Short Interruptions

Item	Test Equipment	Manufacturer	Model No.	Serial No.	Last Cal.
1	Voltage dips and up generator	3CTEST	VDG-1105G	EC0171014	2013/06/18

### 4. POWER LINE CONDUCTED MEASUREMENT

### 4.1.Block Diagram of Test Setup



### 4.2. Conducted Power Line Emission Measurement Standard and Limits

#### 4.2.1.Standard:

EN 55015: 2006+A1: 2007+A2: 2009

#### **4.2.2.Limits**

Frequency	At mains terminals (dBμV)			
Trequency	Quasi-peak Level	Average Level		
9kHz ~ 50kHz	110			
50kHz ~ 150kHz	90 ~ 80*			
150kHz ~ 0.5MHz	66 ~ 56*	56 ~ 46*		
0.5MHz ~ 5.0MHz	56	46		
5.0MHz ~ 30MHz	60	50		

- 1. At the transition frequency the lower limit applies.
- 2. \* decreasing linearly with logarithm of the frequency.

# 4.3.EUT Configuration on Test

The configuration of the EUT is same as Section 3.1.

### 4.4. Operating Condition of EUT

- 4.4.1. Setup the EUT as shown in Section 4.1.
- 4.4.2. Turn on the power of all equipments.
- 4.4.3.Let the EUT work in test mode (On) and measure it.

### 4.5.Test Procedure

The EUT is put on the table which is 0.8 meter high above the ground and connected to the AC mains through a Line Impedance Stabilization Network (L.I.S.N.). This provided a 50ohm coupling impedance for the tested equipments. Both sides of AC line are checked to find out the maximum conducted emission according to the EN 55015 regulations during conducted emission measurement. And the voltage probe had been used for the load terminals measurement according to the EN 55015 standard.

The bandwidth of the test receiver is set at 200Hz in 9k~150kHz range and 9kHz in 150k~30MHz range.

The frequency range from 9kHz to 30MHz is checked.

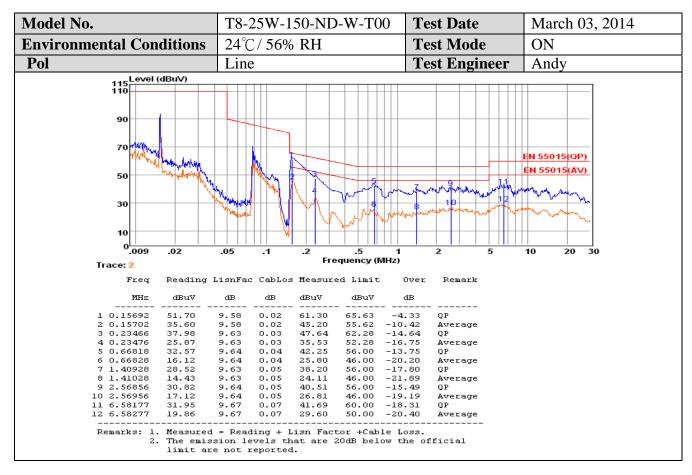
All the test results are listed in Section 4.6.

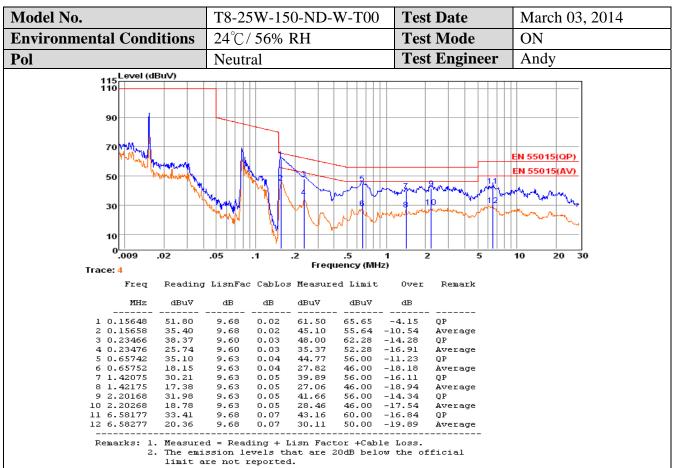
The frequency range from 9kHz to 30MHz is investigated.

### 4.6.Test Results

#### PASS.

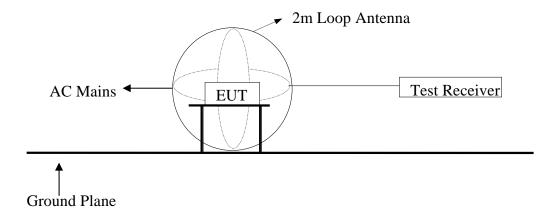
The test result please refer to the next page.





### 5. MAGNETIC FIELD EMISSION MEASUREMENT

### 5.1.Block Diagram of Test Setup



### 5.2. Magnetic Field Emission Measurement Standard and Limits

#### 5.2.1.Test Standard

EN 55015: 2006+A1: 2007+A2: 2009

### 5.2.2.Test Limits

Frequency	Limits for loop diameter (dBµA)
Trequency	2m
9kHz ~ 70kHz	88
70kHz ~ 150kHz	88 ~ 58*
150kHz ~ 3.0MHz	58 ~ 22*
3.0MHz ~ 30MHz	22

- 1. At the transition frequency the lower limit applies.
- 2. \* decreasing linearly with logarithm of the frequency.

# 5.3.EUT Configuration on Test

The configuration of the EUT is same as Section 3.3.

### 5.4. Operating Condition of EUT

Same as conducted measurement which is listed in Section 4.4, except the test set up replaced by Section 5.1.

### 5.5.Test Procedure

The EUT is placed on a wood table in the center of a loop antenna. The induced current in the loop antenna is measured by means of a current probe and the test receiver. Three field components are checked by means of a coaxial switch.

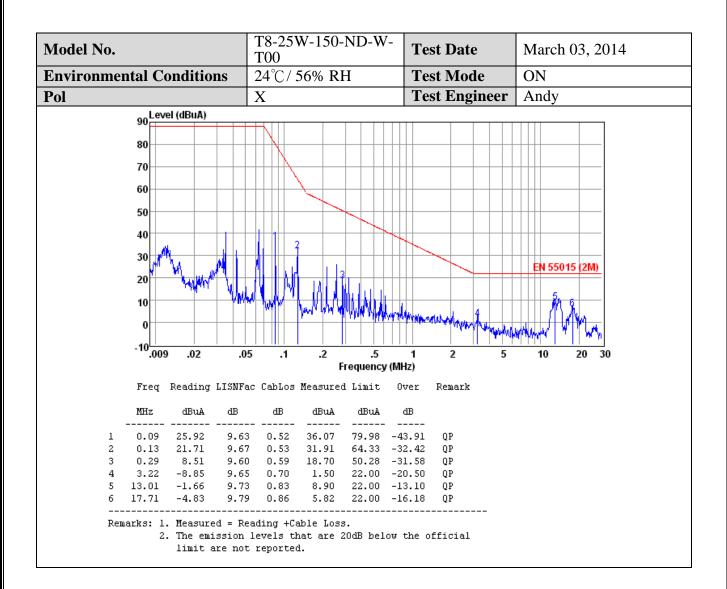
The frequency range from 9kHz to 30MHz is investigated. The receiver is measured with the quasi-peak detector. For frequency band 9kHz to 150kHz, the bandwidth of the field strength meter is set at 200Hz. For frequency band 150kHz to 30MHz, the bandwidth is set at 9kHz.

All the test results are listed in Section 5.6.

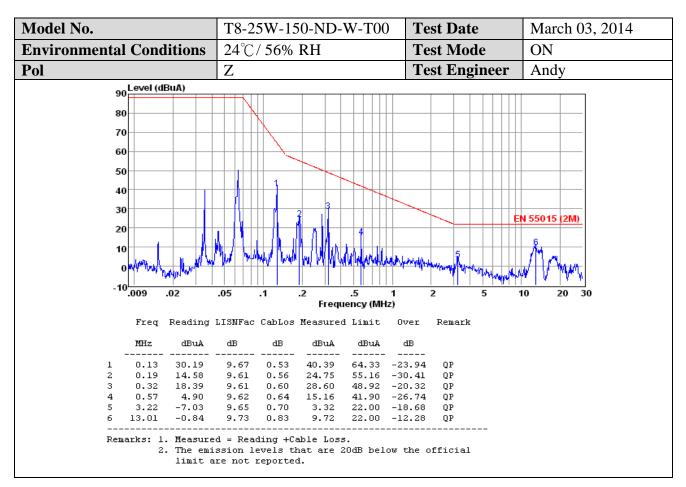
### 5.6.Test Results

#### PASS.

The frequency range from 9kHz to 30MHz is investigated.

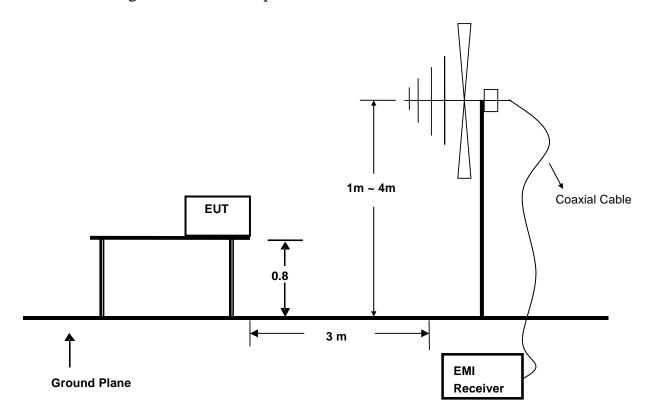


Model No.	T8-25W-1	150-ND-W-T00	<b>Test Date</b>	March 03, 2014
<b>Environmental Condit</b>	tions $24^{\circ}\text{C}/56^{\circ}$	6 RH	Test Mode	ON
Pol	Y		Test Enginee	er Andy
90 Level (dBu	Α)			
80	<del></del>			
70				
60	$\overline{}$			
50				
40	<del></del>			
30	<del>-                                     </del>	3		
20	<del>-                                      </del>	<u>.// // // // // // // // // // // // // </u>		EN 55015 (2M)
10	<u> </u>	<del>. [[]                                  </del>	. 5	<del>                                     </del>
o havenage to the	The while the thinking the	as an All Mark Anthropology	HAMINATURE THE THE PARTY OF THE	AND MAKE
-10 .009 .03	<u> </u>	.2 .5 1	2 5	10 20 30
.009 .0.	2 .05 .1	.2 .5 1 Frequency (MHz)		10 20 30
En a n	Reading LISNFac CabL	W	Over Remark	
_	-			
MHz	dBuA dB dB	dBuA dBuA	dB 	
1 0.13	32.33 9.59 0.5			
	17.93 9.62 0.5			
	20.58 9.62 0.6 6.28 9.63 0.6			
	-5.60 9.65 0.7		_	
6 12.49			_	
	Measured = Reading			
2.	The emission levels		w the official	
	limit are not repor	cea.		



### 6. RADIATED EMISSION MEASUREMENT

# 6.1.Block Diagram of Test Setup



### 6.2.Test Standard

EN 55015: 2006+A1: 2007+A2: 2009

### 6.3. Radiated Emission Limits

All emanations from a class B device or system, including any network of conductors and apparatus connected thereto, shall not exceed the level of field strengths specified below:

FREQUENCY	DISTANCE	FIELD STRENGTHS LIMIT
(MHz)	(Meters)	$(dB\mu V/m)$
30 ~ 230	3	40
230 ~ 300	3	47

Note: (1) The smaller limit shall apply at the combination point between two frequency bands.

(2) Distance refers to the distance in meters between the measuring instrument antenna and the closed point of any part of the EUT.

### 6.4.EUT Configuration on Test

The EN 55015 regulations test method must be used to find the maximum emission during radiated emission measurement.

# 6.5. Operating Condition of EUT

- 6.5.1 Turn on the power.
- 6.5.2 After that, let the EUT work in test mode (ON) and measure it.

### 6.6.Test Procedure

The EUT is placed on a turntable, which is 0.8 meter high above the ground. The turntable can rotate 360 degrees to determine the position of the maximum emission level. The EUT is set 3 meters away from the receiving antenna, which is mounted on an antenna tower. The antenna can be moved up and down from 1 to 4 meters to find out the maximum emission level. By-log antenna (calibrated by Dipole Antenna) is used as a receiving antenna. Both horizontal and vertical polarization of the antenna is set on test.

The bandwidth of the Receiver is set at 120kHz.

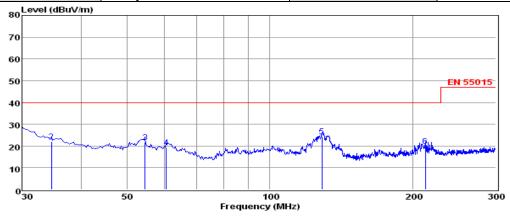
The frequency range from 30MHz to 300MHz is investigated.

### 6.7.Test Results

#### PASS.

The test result please refer to the next page.

Model No.	T8-25W-150-ND-W-T00	Test Date	March 03, 2014
<b>Environmental Conditions</b>	24°C / 56% RH	Test Mode	ON
Pol	Vertical	<b>Detector Function</b>	Quasi-peak
<b>Test Engineer</b>	Andy	Distance	3m

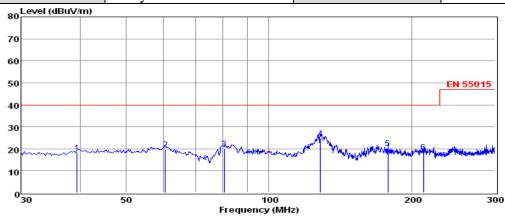


	Freq	Reading	CabLos	Antfac	Measured	Limit	Over	Remark
	MHz	dBuV	dВ	dB/m	dBuV/m	dBuV/m	dВ	
1	30.00	14.34	0.39	12.33	27.06	40.00	-12.94	QP
2	34.59	9.43	0.41	12.30	22.14	40.00	-17.86	QP
3	54.57	8.34	0.46	13.04	21.84	40.00	-18.16	QP
4	60.51	6.49	0.49	12.49	19.47	40.00	-20.53	QP
5	128.82	14.53	0.67	9.11	24.31	40.00	-15.69	QP
6	212.79	8.02	0.95	10.97	19.94	40.00	-20.06	QP

Note: 1. All readings are Quasi-peak values. 2. Measured= Reading + Antenna Factor + Cable Loss

3. The emission that ate 20db blow the offficial limit are not reported

Model No.	T8-25W-150-ND-W-T00	Test Date	March 03, 2014
<b>Environmental Conditions</b>	24°C / 56% RH	Test Mode	ON
Pol	Horizontal	<b>Detector Function</b>	Quasi-peak
Test Engineer	Andy	Distance	3m



	Freq	Reading	CabLos	Antfac	Measured	Limit	Over	Remark
	MHz	dBuV	dВ	dB/m	dBuV/m	dBuV/m	dВ	
1	39.45	4.44	0.38	13.44	18.26	40.00	-21.74	QP
2	60.51	6.60	0.49	12.49	19.58	40.00	-20.42	QP
3	80.49	10.47	0.65	8.71	19.83	40.00	-20.17	QP
4	128.55	14.90	0.67	9.15	24.72	40.00	-15.28	QP
5	178.23	9.78	0.89	9.55	20.22	40.00	-19.78	QP
6	211.98	6.54	0.93	10.95	18.42	40.00	-21.58	QP

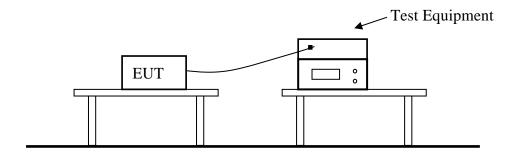
Note: 1. All readings are Quasi-peak values.

2. Measured= Reading + Antenna Factor + Cable Loss

3. The emission that ate 20db blow the offficial limit are not reported

# 7. HARMONIC CURRENT MEASUREMENT

# 7.1.Block Diagram of Test Setup



### 7.2.Test Standard

EN 61000-3-2: 2006+A1: 2009+A2: 2009

# 7.3. Operating Condition of EUT

Same as Section 4.4. except the test setup replaced by Section 7.1.

### 7.4.Test Results

### PASS.

The test result please refer to the next page.

Model No.		T8-25W-150-ND-W-T00	Test Date	March 03, 2014
Test Engineer		Andy		
Type of Test:	EN610	000:2006 Harmonics inc. interharmonics to E	N61000-4-7:200	2
Limits:	Class	C > 25W		
Power Analyzer:	Volted Channel	h PM6000 SN: 200006700523 Firmware (s):	version: v1.21.0	7RC2
	1. SN: 09	90015502053, 28 Adjusted Date: 22 JUN 2011. 2. SN:None	Adjusted Date:None	
	3. SN:No	one Adjusted Date:None 4. SN:None Adjusted Date:None		
	5. SN:No	one Adjusted Date:None 6. SN:None Adjusted Date:None		
	Shunt(s)	:		
	1. SN: 09	91024301916, 4 Adjusted Date: 23 JUN 2011. 2. SN:None A	djusted Date:None	
	3. SN:No	one Adjusted Date:None 4. SN:None Adjusted Date:None		
	5. SN:No	one Adjusted Date:None 6. SN:None Adjusted Date:None		
AC Source:	Mains	/ Manual Source		
Harmonic Results Against Chosen Lii	mits:	Notes:		

**PASS** 

Test Parameter Details	User Entered	Measured
Operating Frequency:	50	49.9840
Operating Voltage:	230	229.0900
Specified Power:	0.0000	25.4355
Fundamental Current:	0.1180	0.1179
Power Factor:	0.9800	0.9750
Average Input Current:		0.1181
Maximum POHC:		0.0030
POHC Limit:		0.0112
Maximum THC:		0.0077
Minimum Power:	75	
Class Multiplier:	1.0000	
Test Duration:	00:03:00	

### Voltech IEC61000-3 Windows Software 1.14.06RC1

Type of Test: Fluctuating Harmonics Test - Source Qualification (2006)

Power Analyzer: Voltech PM6000 SN: 200006700523 Firmware version: v1.21.07RC2

Channel(s):

3. SN:None Adjusted Date:None 4. SN:None Adjusted Date:None5. SN:None Adjusted Date:None 6. SN:None Adjusted Date:None

Shunt(s):

1. SN: 091024301916, 4 Adjusted Date: 23 JUN 2011. 2. SN:None Adjusted Date:None

3. SN:None Adjusted Date:None 4. SN:None Adjusted Date:None5. SN:None Adjusted Date:None 6. SN:None Adjusted Date:None

AC Source: Mains / Manual Source

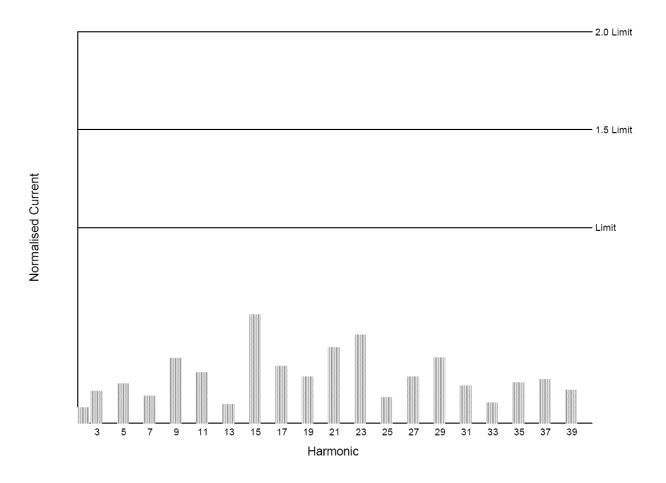
Overall Result:

**PASS** 

	Nominal	Measured	Measured Deviation Allowe		Result
				Deviation	
Supply Voltage	230.00V	229.09V	0.91V	4.60V	Pass
Supply Frequency	50.00Hz	49.98Hz	0.02Hz	0.25Hz	Pass
Crest Factor	1.4100	1.4197	0.0097	+/- 0.01	Pass

Harmonic	Reading	Limit	Result	Harmonic	Reading	Limit	Result
2	0.09%	0.20%	Pass	3	0.04%	0.90%	Pass
4	0.03%	0.20%	Pass	5	0.04%	0.40%	Pass
6	0.02%	0.20%	Pass	7	0.05%	0.30%	Pass
8	0.03%	0.20%	Pass	9	0.04%	0.20%	Pass
10	0.02%	0.20%	Pass	11	0.03%	0.10%	Pass
12	0.01%	0.10%	Pass	13	0.01%	0.10%	Pass
14	0.01%	0.10%	Pass	15	0.03%	0.10%	Pass
16	0.01%	0.10%	Pass	17	0.01%	0.10%	Pass
18	0.01%	0.10%	Pass	19	0.02%	0.10%	Pass
20	0.01%	0.10%	Pass	21	0.03%	0.10%	Pass
22	0.01%	0.10%	Pass	23	0.01%	0.10%	Pass
24	0.01%	0.10%	Pass	25	0.02%	0.10%	Pass
26	0.01%	0.10%	Pass	27	0.03%	0.10%	Pass
28	0.01%	0.10%	Pass	29	0.01%	0.10%	Pass
30	0.01%	0.10%	Pass	31	0.01%	0.10%	Pass
32	0.01%	0.10%	Pass	33	0.01%	0.10%	Pass
34	0.01%	0.10%	Pass	35	0.01%	0.10%	Pass
36	0.01%	0.10%	Pass	37	0.03%	0.10%	Pass
38	0.01%	0.10%	Pass	39	0.03%	0.10%	Pass
40	0.01%	0.10%	Pass				

Voltech IEC61000-	-3 Windows Software 1.14.06RC1									
Type of Test:	Fluctuating Harmonics Test - Normalised Worst Case Bar Chart (2006)									
Power Analyzer:	Voltech PM6000 SN: 200006700523 Firmware version: v1.21.07RC2									
	Channel(s):									
	1. SN: 090015502053, 28 Adjusted Date: 22 JUN 2011. 2. SN:None Adjusted Date:None									
	3. SN:None Adjusted Date:None 4. SN:None Adjusted Date:None									
	5. SN:None Adjusted Date:None 6. SN:None Adjusted Date:None									
	Shunt(s):									
	1. SN: 091024301916, 4 Adjusted Date: 23 JUN 2011. 2. SN:None Adjusted Date:None									
	3. SN:None Adjusted Date:None 4. SN:None Adjusted Date:None									
	5. SN:None Adjusted Date:None 6. SN:None Adjusted Date:None									
AC Source:	Mains / Manual Source									
Overall Result:										
D.4.0.0										
PASS										
Class	Class C > 25W									
Class Multiplier	1									



Voltech IEC61000-3 Windows Software 1.14.06RC1

Type of Test: Fluctuating Harmonics Test - Worst Case Table (2006)

Power Analyzer: Voltech PM6000 SN: 200006700523 Firmware version: v1.21.07RC2

Channel(s):

1. SN: 090015502053, 28 Adjusted Date: 22 JUN 2011. 2. SN:None Adjusted Date:None

3. SN:None Adjusted Date:None 4. SN:None Adjusted Date:None 5. SN:None Adjusted Date:None 6. SN:None Adjusted Date:None

Shunt(s):

1. SN: 091024301916, 4 Adjusted Date: 23 JUN 2011. 2. SN:None Adjusted Date:None

3. SN:None Adjusted Date:None 4. SN:None Adjusted Date:None5. SN:None Adjusted Date:None 6. SN:None Adjusted Date:None

AC Source: Mains / Manual Source

Overall Result:

**PASS** 

Class	Class C > 25W
Class Multiplier	1

Harm	Limit 1	Limit 2	Average Reading	<l1 <l2<="" th=""><th>Max Reading</th><th><l2< th=""><th>Pass FAIL</th><th>Harm</th><th>Limit 1</th><th>Limit 2</th><th>Average Reading</th><th><l1 <l2<="" th=""><th>Max Reading</th><th><l2< th=""><th>Pass FAIL</th></l2<></th></l1></th></l2<></th></l1>	Max Reading	<l2< th=""><th>Pass FAIL</th><th>Harm</th><th>Limit 1</th><th>Limit 2</th><th>Average Reading</th><th><l1 <l2<="" th=""><th>Max Reading</th><th><l2< th=""><th>Pass FAIL</th></l2<></th></l1></th></l2<>	Pass FAIL	Harm	Limit 1	Limit 2	Average Reading	<l1 <l2<="" th=""><th>Max Reading</th><th><l2< th=""><th>Pass FAIL</th></l2<></th></l1>	Max Reading	<l2< th=""><th>Pass FAIL</th></l2<>	Pass FAIL
2	2.360mA	3.540mA	0.174mA	<b>✓</b> ✓	0.194mA	<b>\</b>	N/A	3	34.69mA	52.03mA	5.660mA	<b>√</b> √	5.726mA	>	Pass
4	None	None	0.120mA		0.135mA		N/A	5	11.79mA	17.69mA	2.389mA	<b>✓</b> ✓	2.411mA	<	N/A
6	None	None	0.131mA		0.151mA		N/A	7	8.259mA	12.38mA	1.133mA	<b>✓</b> ✓	1.153mA	<b>✓</b>	N/A
8	None	None	0.117mA		0.137mA		N/A	9	5.900mA	8.849mA	1.942mA	<b>✓</b> ✓	1.966mA	<b>✓</b>	N/A
10	None	None	0.111mA		0.124mA		N/A	11	3.540mA	5.310mA	0.896mA	<b>✓</b> ✓	0.917mA	<b>✓</b>	N/A
12	None	None	0.173mA		0.191mA		N/A	13	3.540mA	5.310mA	0.304mA	<b>✓</b> ✓	0.344mA	<b>✓</b>	N/A
14	None	None	0.117mA		0.134mA		N/A	15	3.540mA	5.310mA	1.946mA	<b>✓</b> ✓	1.965mA	>	N/A
16	None	None	0.110mA		0.122mA		N/A	17	3.540mA	5.310mA	1.006mA	<b>✓</b> ✓	1.032mA	>	N/A
18	None	None	0.112mA		0.126mA		N/A	19	3.540mA	5.310mA	0.817mA	<b>✓</b> ✓	0.840mA	<b>\</b>	N/A
20	None	None	0.119mA		0.135mA		N/A	21	3.540mA	5.310mA	1.351mA	<b>/ /</b>	1.371mA	<b>✓</b>	N/A
22	None	None	0.119mA		0.136mA		N/A	23	3.540mA	5.310mA	1.578mA	<b>✓</b> ✓	1.599mA	<b>\</b>	N/A
24	None	None	0.163mA		0.180mA		N/A	25	3.540mA	5.310mA	0.441mA	<b>✓</b> ✓	0.465mA	<b>\</b>	N/A
26	None	None	0.115mA		0.127mA		N/A	27	3.540mA	5.310mA	0.826mA	<b>✓</b> ✓	0.846mA	<b>\</b>	N/A
28	None	None	0.114mA		0.135mA		N/A	29	3.540mA	5.310mA	1.174mA	<b>/ /</b>	1.191mA	<b>✓</b>	N/A
30	None	None	0.114mA		0.126mA		N/A	31	3.540mA	5.310mA	0.657mA	<b>/ /</b>	0.683mA	<b>✓</b>	N/A
32	None	None	0.117mA		0.129mA		N/A	33	3.540mA	5.310mA	0.356mA	<b>/ /</b>	0.374mA	<b>✓</b>	N/A
34	None	None	0.114mA		0.128mA		N/A	35	3.540mA	5.310mA	0.724mA	<b>/ /</b>	0.742mA	<b>✓</b>	N/A
36	None	None	0.136mA		0.154mA		N/A	37	3.540mA	5.310mA	0.777mA	<b>✓</b> ✓	0.796mA	<b>✓</b>	N/A
38	None	None	0.115mA		0.129mA		N/A	39	3.540mA	5.310mA	0.580mA	<b>✓</b> ✓	0.606mA	<b>✓</b>	N/A
40	None	None	0.123mA		0.136mA		N/A								

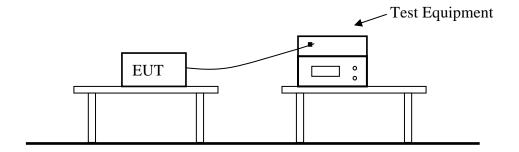
<sup>&</sup>lt;L1 : Reading is below limit 1.

<sup>&</sup>lt;L2 : Reading is below limit 2.

 $<sup>\</sup>label{eq:normalized} \text{N/A}: \text{Harmonic current below 0.6\% of rated current or 5mA, whichever is greater, are disregarded.}$ 

# 8. VOLTAGE FLUCTUATIONS & FLICKER MEASUREMENT

# 8.1.Block Diagram of Test Setup



### 8.2.Test Standard

EN 61000-3-3: 2008

# 8.3. Operating Condition of EUT

Same as Section 4.4. except the test setup replaced by Section 8.1.

### 8.4.Test Results

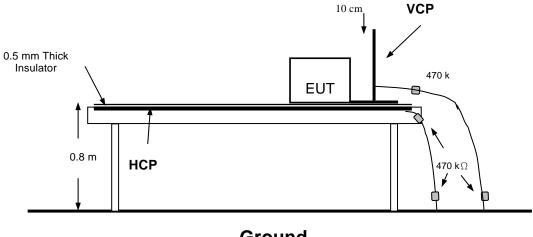
### PASS.

The test result please refer to the next page.

Model No.	T8-25W	-150-ND-W-T00	<b>Test Date</b>	March 03, 2014							
Test Engineer	Andy										
Type of Test:	Flickermeter Te	Flickermeter Test - Table									
Power Analyzer:	07RC2										
	1. SN: 090015502053,	28 Adjusted Date: 22 JUN 2011. 2. SN	N:None Adjusted Date:None								
	3. SN:None Adjusted	Date:None 4. SN:None Adjusted Date	te:None								
	5. SN:None Adjusted	Date:None 6. SN:None Adjusted Date	te:None								
	Shunt(s):										
	1. SN: 091024301916,	4 Adjusted Date: 23 JUN 2011. 2. SN:	None Adjusted Date:None								
	3. SN:None Adjusted	Date:None 4. SN:None Adjusted Date	e:None								
	5. SN:None Adjusted	Date:None 6. SN:None Adjusted Date	e:None								
AC Source:	Mains / Manual	Source									
Overall Result:	Notes:										
	Measurement m	ethod - Voltage									
PASS											
	Pst	dc (%)	dmax (%)	d(t) > 3.3%(ms)							
Limit	1.000	3.300	4.000	500							
Reading 1	0.090	0.008	0.125	0							

# 9. ELECTROSTATIC DISCHARGE TEST

# 9.1.Block Diagram of Test Setup



### Ground

### 9.2.Test Standard

EN 61547: 2009 (EN 61000-4-2: 2009, Severity Level: Air Discharge: Level 3, ±8KV Contact Discharge: Level 2, ±4KV)

### 9.3. Severity Levels and Performance Criterion

### 9.3.1.Severity level

Level	Test Voltage	Test Voltage		
	Contact Discharge (KV)	Air Discharge (KV)		
1.	±2	±2		
2.	<u>±</u> 4	±4		
3.	±6	±8		
4.	±8	±15		
X	Special	Special		

### 9.3.2.Performance criterion: **B**

# 9.4.EUT Configuration on Test

The configuration of EUT is listed in Section 3.7.

### 9.5. Operating Condition of EUT

- 9.5.1. Setup the EUT as shown in Section 9.1.
- 9.5.2. Turn on the power of all equipments.
- 9.5.3.Let the EUT work in test mode (ON) and measure it.

#### 9.6.Test Procedure

### 9.6.1.Air Discharge

This test is done on a non-conductive surfaces. The round discharge tip of the discharge electrode shall be approached as fast as possible to touch the EUT. After each discharge, the discharge electrode shall be removed from the EUT. The generator is then re-triggered for a new single discharge and repeated 10 times for each pre-selected test point. This procedure shall be repeated until all the air discharge completed.

Because the case of the EUT is metal surface, so it does not need to be tested.

### 9.6.2.Contact Discharge

All the procedure shall be same as Section 9.6.1. except that the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.

### 9.6.3.Indirect Discharge For Horizontal Coupling Plane

At least 20 single discharges shall be applied to the horizontal coupling plane, at points on each side of the EUT. The discharge electrode positions vertically at a distance of 0.1m from the EUT and with the discharge electrode touching the coupling plane.

### 9.6.4.Indirect Discharge For Vertical Coupling Plane

At least 20 single discharge shall be applied to the center of one vertical edge of the coupling plane. The coupling plane, of dimensions 0.5m X 0.5m, is placed parallel to, and positioned at a distance of 0.1m from the EUT. Discharges shall be applied to the coupling plane, with this plane in sufficient different positions that the four faces of the EUT are completely illuminated.

### 9.7.Test Results

#### PASS.

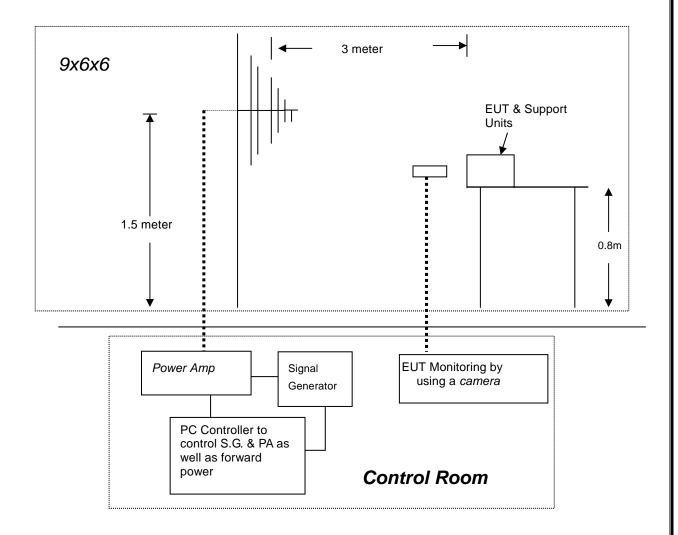
Please refer to the following page.

Report No.	LCS140225048	$\mathbf{F}$
Ticport 110.	LCDITULLIO	ட

Electrostatic Discharger Test Results							
Standard	☐ IEC 61000-4-2						
Applicant	Applicant TEA-Energy China Limited						
EUT	T8 LED Tube	<b>;</b>		Tempe	rature	26℃	
M/N	T8-25W-150-	ND-W-T00	)	Humid	lity	51%	
Criterion	В			Pressu	re	1021mb	oar
Test Mode	Normal			Test Da	Test Date March 03, 201		
Test Engineer	Andy						<u> </u>
S	<u> </u>		' D' 1				
		A Test Levels	ir Discharge	2	Re	sults	
<b>Test Points</b>	± 2KV	± 4KV	± 8KV	Pass	Fail	Perfo	ormance
Front						Crite	
Back		$\square$					=
Left				$\boxtimes$			
Right							
Тор		$\boxtimes$		$\boxtimes$			
Bottom		$\boxtimes$		$\boxtimes$			=
		Con	tact Dischar	rge			
		Test Levels			Re	sults	
<b>Test Points</b>	± 2 KV		±4 KV	Pass	Fail	Perfo	ormance erion
Front	$\boxtimes$		$\boxtimes$	$\boxtimes$			∆ ⊠B
Back			$\boxtimes$	$\boxtimes$		A	
Left	$\square$		$\boxtimes$	$\square$		A	
Right			$\boxtimes$			A	<del></del> -
Тор						A	
Bottom						A	∆ ⊠B
			o Horizonta	l Coupling			
		Test Levels	<u> </u>		Re	sults	
Side of EUT	± 2 KV	:	± 4 KV	Pass	Fail	Perfo Crite	rmance rion
Front			$\boxtimes$				∆ ⊠B
Back			$\boxtimes$	$\boxtimes$			$\boxtimes \mathbf{B}$
Left	$\boxtimes$		$\boxtimes$	$\boxtimes$		A	⊠B
Right	$\boxtimes$		$\boxtimes$				⊠B
Discharge To Vertical Coupling Plane							
		Test Levels	<u> </u>		Re	sults	
Side of EUT	± 2 KV		± 4 KV	Pass	Fail	Perfo Crite	rmance rion
Front			$\boxtimes$			A	
Back			$\boxtimes$			A	
Left			$\boxtimes$			A	
Right			$\boxtimes$	$\boxtimes$		$\Box$ A	$\boxtimes \mathbf{B}$

# 10. RF FIELD STRENGTH SUSCEPTIBILITY TEST

# 10.1.Block Diagram of Test Setup



### 10.2.Test Standard

EN 61547: 2009 (EN 61000-4-3: 2006+A1: 2008, Severity Level: 2, 3V / m)

# 10.3. Severity Levels and Performance Criterion

### 10.3.1. Severity level

Level	Field Strength (V/m)		
1	1		
2	3		
3	10		
X	Special		

10.3.2.Performance criterion: A

### 10.4.EUT Configuration on Test

The configuration of EUT are listed in Section 3.8.

## 10.5. Operating Condition of EUT

- 10.5.1. Setup the EUT as shown in Section 10.1.
- 10.5.2. Turn on the power of all equipments.
- 10.5.3.Let the EUT work in test mode (On) and measure it.

### 10.6.Test Procedure

The EUT and its simulators are placed on a turn table which is 0.8 meter above ground. EUT is set 3 meter away from the transmitting antenna which is mounted on an antenna tower. Both horizontal and vertical polarization of the antenna are set on test. Each of the four sides of EUT must be faced this transmitting antenna and measured individually. In order to judge the EUT performance, a CCD camera is used to monitor EUT screen. All the scanning conditions are as follows:

Condition of Test		Remarks		
1.	Fielded Strength	3 V/m (Severity Level 2)		
2.	Radiated Signal	Unmodulated		
3.	Scanning Frequency	80 - 1000 MHz		
4.	Dwell time of radiated	0.0015 decade/s		
5.	Waiting Time	3 Sec.		

### 10.7.Test Results

#### PASS.

Please refer to the following page.

#### RF Field Strength Susceptibility Test Results ☐ IEC 61000-4-3 Standard ☑ EN 61000-4-3 **Applicant TEA-Energy China Limited EUT** T8 LED Tube **Temperature** 26°C 51% M/N T8-25W-150-ND-W-T00 Humidity **Field Strength** 3 V/m Criterion A **Test Mode** Normal **Test Engineer** Andy 80 MHz to 1000 MHz March 03, 2014 **Frequency Range Test Date Modulation** □None □ Pulse ☑AM 1KHz 80%

	Horizontal	Vertical
Front	PASS	PASS
Right	PASS	PASS
Rear	PASS	PASS
Left	PASS	PASS

1%

### Test Equipment:

1. Signal Generator: 2031 (MARCONI)

Power Amplifier: 500A100 & 100W/1000M1 (A&R)
 Power Antenna: 3108 (EMCO) & AT1080 (A&R)

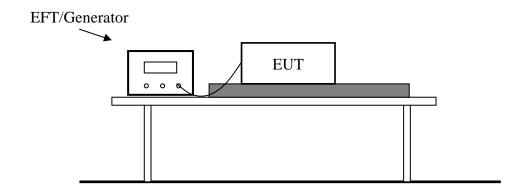
4. Field Monitor: FM2000 (A&R)

TA 1	r		
	$\alpha$	tΔ	•
1.7	•	ιL	

**Steps** 

### 11. ELECTRICAL FAST TRANSIENT/BURST TEST

# 11.1.Block Diagram of Test Setup



### 11.2.Test Standard

EN 61547: 2009 (EN 61000-4-4: 2004+A1: 2010, Severity Level: Level 2: 1KV)

### 11.3. Severity Levels and Performance Criterion

### 11.3.1.Severity level

Open Circuit Output Test Voltage ±10%				
Level	On Power Supply	On I/O (Input/Output)		
	Lines	Signal data and control lines		
1.	0.5 KV	0.25 KV		
2.	1 KV	0.5 KV		
3.	2 KV	1 KV		
4.	4 KV	2 KV		
X	Special	Special		

### 11.3.2.Performance criterion: **B**

# 11.4.EUT Configuration on Test

The configuration of EUT are listed in Section 3.9.

### 11.5. Operating Condition of EUT

- 11.5.1. Setup the EUT as shown in Section 11.1.
- 11.5.2. Turn on the power of all equipments.
- 11.5.3.Let the EUT work in test mode (ON) and measure it.

#### 11.6.Test Procedure

The EUT is put on the table which is 0.8 meter high above the ground. This reference ground plane shall project beyond the EUT by at least 0.1m on all sides and the minimum distance between EUT and all other conductive structure, except the ground plane beneath the EUT, shall be more than 0.5m.

### 11.6.1. For input and output AC power ports:

The EUT is connected to the power mains by using a coupling device which couples the EFT interference signal to AC power lines. Both polarities of the test voltage should be applied during compliance test and the duration of the test is 2 mins.

#### 11.6.2.For signal lines and control lines ports:

No I/O ports. It's unnecessary to test.

#### 11.6.3. For DC output line ports:

It's unnecessary to test.

#### 11.7.Test Results

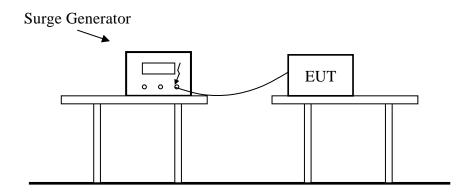
#### PASS.

Electrical Fast Transient/Burst Test Results				
Standard	□ IEC 61000-4-4			
Applicant	TEA-Energy China Limited			
EUT	T8 LED Tube	Temperature	26℃	
M/N	T8-25W-150-ND-W-T00	Humidity	51%	
Test Mode	Normal	Criterion	В	
Test Engineer	Andy	Test Date	March 03, 2014	

Line	Test Voltage	Result (+)	Result (-)
L	1KV	PASS	PASS
N	1KV	PASS	PASS
PE			
L-N	1KV	PASS	PASS
L-PE			
N-PE			
L-N-PE			
Signal Line			
I/O Cable			
Note:		,	

### 12. SURGE IMMUNITY TEST

## 12.1.Block Diagram of Test Setup



### 12.2.Test Standard

EN 61547: 2009 (EN61000-4-5: 2006, Severity Level: Line to Line: Level 2, 1.0KV; Line to Earth: Level 3, 2.0KV)

## 12.3. Severity Levels and Performance Criterion

### 12.3.1.Severity level

Severity Level	Open-Circuit Test Voltage	
	(KV)	
1	0.5	
2	1.0	
3	2.0	
4	4.0	
*	Special	

### 12.3.2.Performance criterion: **B**

# 12.4.EUT Configuration on Test

The configuration of EUT are listed in Section 3.10.

### 12.5. Operating Condition of EUT

- 12.5.1. Setup the EUT as shown in Section 12.1.
- 12.5.2. Turn on the power of all equipments.
- 12.5.3.Let the EUT work in test mode (ON) and measure it.

#### 12.6.Test Procedure

- 12.6.1. Set up the EUT and test generator as shown on Section 12.1.
- 12.6.2.For line to line coupling mode, provide a1.0KV 1.2/50us voltage surge (at open-circuit condition) and 8/20us current surge to EUT selected points.
- 12.6.3.At least 5 positive and 5 negative (polarity) tests with a maximum 1/min repetition rate are conducted during test.
- 12.6.4. Different phase angles are done individually.
- 12.6.5.Record the EUT operating situation during compliance test and decide the EUT immunity criterion for above each test.

### 12.7.Test Results

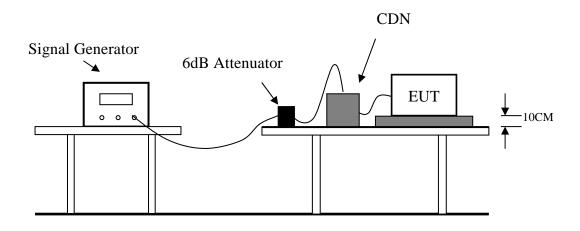
PASS.

Surge Immunity Test Result				
Standard	dard □ IEC 61000-4-5 □ EN 61000-4-5			
Applicant	TEA-Energy China Limited			
EUT	T8 LED Tube Temperature 26℃			
M/N	T8-25W-150-ND-W-T00 <b>Humidity</b> 51%			
Test Mode	Normal Criterion B			
Test Engineer	Andy Test Date March 03, 2014			

Location	Polarity	Phase Angle	Number of Pulse	Pulse Voltage (KV)	Result
	+	$0_{\rm o}$	5	1.0	PASS
	+	90°	5	1.0	PASS
	+	180°	5	1.0	PASS
T NI	+	270°	5	1.0	PASS
L-N	-	$0_{\rm o}$	5	1.0	PASS
	-	90°	5	1.0	PASS
	-	180°	5	1.0	PASS
	-	270°	5	1.0	PASS
L-PE N-PE					
Signal Line					
Note					

## 13. INJECTED CURRENTS SUSCEPTIBILITY TEST

## 13.1.Block Diagram of Test Setup



### 13.2.Test Standard

EN 61547: 2009 (EN 61000-4-6: 2009, Severity Level: 3V (rms), 0.15MHz ~ 80MHz)

### 13.3. Severity Levels and Performance Criterion

### 13.3.1. Severity level

Level	Field Strength (V)	
1.	1	
2.	3	
3.	10	
X	Special	

#### 13.3.2.Performance criterion: A

## 13.4.EUT Configuration on Test

The configuration of EUT are listed in Section 3.11.

### 13.5. Operating Condition of EUT

- 13.5.1. Setup the EUT as shown in Section 13.1.
- 13.5.2. Turn on the power of all equipments.
- 13.5.3.Let the EUT work in test mode (ON) and measure it.

#### 13.6.Test Procedure

- 13.6.1. Set up the EUT, CDN and test generators as shown on Section 13.1.
- 13.6.2.Let the EUT work in test mode and measure it.
- 13.6.3. The EUT are placed on an insulating support 0.1m high above a ground reference plane. CDN (coupling and decoupling device) is placed on the ground plane about 0.3m from EUT. Cables between CDN and EUT are as short as possible, and their height above the ground reference plane shall be between 30 and 50 mm (where possible).
- 13.6.4. The disturbance signal described below is injected to EUT through CDN.
- 13.6.5. The EUT operates within its operational mode(s) under intended climatic conditions after power on.
- 13.6.6. The frequency range is swept from 150kHz to 80MHz using 3V signal level, and with the disturbance signal 80% amplitude modulated with a 1kHz sine wave.
- 13.6.7. The rate of sweep shall not exceed 1.5\*10-3decades/s. Where the frequency is swept incrementally, the step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value.
- 13.6.8.Recording the EUT operating situation during compliance testing and decide the EUT immunity criterion.

### 13.7.Test Results

#### PASS.

Injected Currents Susceptibility Test Results				
Standard	☐ IEC 61000-4-6			
Applicant	TEA-Energy China Limited			
EUT	T8 LED Tube Temperature 26°C			
M/N	T8-25W-150-ND-W-T00 <b>Humidity</b> 51%			
<b>Test Mode</b>	Normal Criterion A			
<b>Test Engineer</b>	Andy Test Date March 03, 2014			

Frequency Range (MHz)	Injected Position	Strength (Unmodulated)	Criterion	Result
0.15 ~ 80	AC Mains	3V	A	PASS

### Remark:

Note:

1. Modulation Signal:1kHz 80% AM

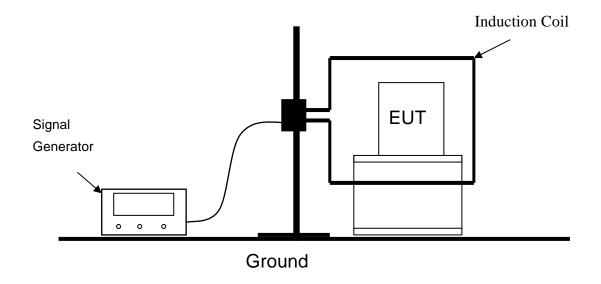
2. Measurement Equipment:

Simulator: CIT-10 (FRANKONIA)

CDN : ☑DN-M2 (FRANKONIA) ☐CDN-M3 (FRANKONIA)

# 14. MAGNETIC FIELD IMMUNITY TEST

# 14.1.Block Diagram of Test Setup



### 14.2.Test Standard

EN 61547: 2009 (EN 61000-4-8: 2010, Severity Level 2: 3A/m)

### 14.3. Severity Levels and Performance Criterion

### 14.3.1. Severity level

Level	Magnetic Field Strength (A/m)
1.	1
2.	3
3.	10
4.	30
5.	100
X	Special

#### 14.3.2.Performance criterion: A

# 14.4.EUT Configuration on Test

The configuration of EUT are listed in Section 3.12.

# 14.5. Operating Condition of EUT

- 14.5.1. Setup the EUT as shown in Section 14.1.
- 14.5.2. Turn on the power of all equipments.
- 14.5.3.Let the EUT work in test mode (On) and measure it.

#### 14.6.Test Procedure

- 14.6.1.Set up the EUT system as shown on Section 14.1.
- 14.6.2. The Induction coil is set up in horizontal or vertical.
- 14.6.3.Let the EUT work in test mode and measure it.

### 14.7.Test Results

#### PASS.

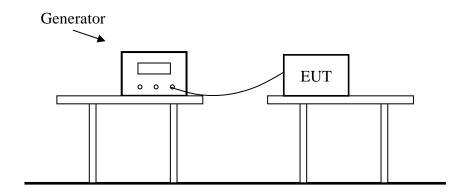
Magnetic Field Immunity Test Result				
Standard	□ IEC 61000-4-8			
Applicant	TEA-Energy China Limited			
EUT	T8 LED Tube	Temperature	26℃	
M/N	T8-25W-150-ND-W-T00	Humidity	51%	
Test Mode	Normal	Criterion	A	
Test Engineer	Andy	Test Date	March 03, 2014	

Test Level (A/M)	Testing Duration	Coil Orientation	Criterion	Result
3	5 mins	X	A	PASS
3	5 mins	Y	A	PASS
3	5 mins	Z	A	PASS

Note:

# 15. VOLTAGE DIPS AND INTERRUPTIONS TEST

## 15.1.Block Diagram of Test Setup



### 15.2.Test Standard

EN 61547: 2009 (EN 61000-4-11: 2004)

### 15.3. Severity Levels and Performance Criterion

### 15.3.1. Severity level

Test Level (%U <sub>T</sub> )	Voltage dip and short interruptions (%U <sub>T</sub> )	Duration (in period)
0	100	0.5
70	30	10

### 15.3.2.Performance criterion: **B&C**

# 15.4.EUT Configuration on Test

The configuration of EUT are listed in Section 3.13&3.14.

# 15.5.Operating Condition of EUT

- 15.5.1. Setup the EUT as shown in Section 15.1.
- 15.5.2. Turn on the power of all equipments.
- 15.5.3.Let the EUT work in test mode (ON) and measure it.

#### 15.6.Test Procedure

- 15.6.1. Set up the EUT and test generator as shown on Section 15.1.
- 15.6.2. The interruptions is introduced at selected phase angles with specified duration.
- 15.6.3.Record any degradation of performance.

### 15.7.Test Result

#### PASS.

Voltage Dips And Interruptions Test Results			
Standard	□ IEC 61000-4-11 □ EN 61000-4-11		
Applicant	TEA-Energy China Limited		
EUT	T8 LED Tube	Temperature	26℃
M/N	T8-25W-150-ND-W-T00	Humidity	51%
Test Mode	Normal	Criterion	B&C
<b>Test Engineer</b>	Andy	<b>Test Date</b>	March 03, 2014

Test Level % U <sub>T</sub>	Voltage Dips & Short Interruptions % U <sub>T</sub>	Duration (in periods)	Criterion	Result
0	100	0.5P	В	PASS
70	30	10P	С	PASS

Note:

# 16. PHOTOGRAPH

## 16.1. Photo of Power Line Conducted Measurement



16.2. Photo of Radiated Electromagnetic Disturbance Measurement



### 16.3. Photo of Radiated Measurement



## 16.4. Photo of Harmonic & Flicker Measurement



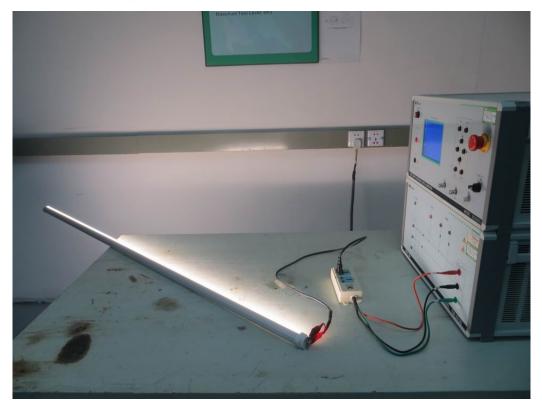
# 16.5. Photo of Electrostatic Discharge Test



## 16.6. Photo of Electrical Fast Transient/Burst Test



# 16.7. Photo of Surge Immunity Test



16.8. Photo of Injected Currents Susceptibility Test



## 16.9. Photo of Magnetic Field Immunity Test



16.10. Photo of Voltage Dips and Short Interruptions Immunity Test



# 17. EXTERNAL AND INTERNAL PHOTOS OF THE EUT

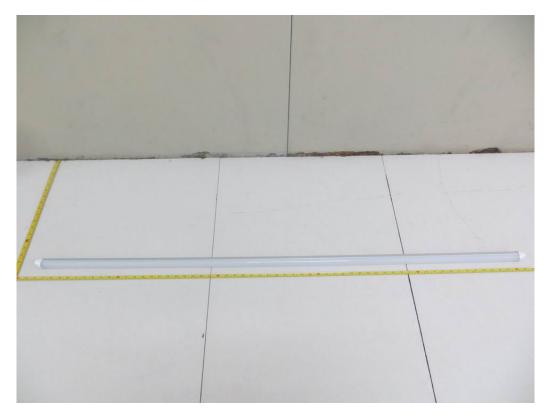


Fig 1



Fig 2



Fig 3



Fig 4

# 18. MANUFACTURER/ APPROVAL HOLDER DECLARATION

The following identical model(s):

T8-9W-60-ND-W-T00	T8-9W-60-D-W-T00	T8-9W-60-S-W-T00
T8-9W-60-ND-NW-T00	T8-9W-60-D-NW-T00	T8-9W-60-S-NW-T00
T8-9W-60-ND-WW-T00	T8-9W-60-D-WW-T00	T8-9W-60-S-WW-T00
T8-9W-60-ND-W-F00	T8-9W-60-D-W-F00	T8-9W-60-S-W-F00
T8-9W-60-ND-NW-F00	T8-9W-60-D-NW-F00	T8-9W-60-S-NW-F00
T8-9W-60-ND-WW-F00	T8-9W-60-D-WW-F00	T8-9W-60-S-WW-F00
T8-9W-60-ND-W-W00	T8-9W-60-D-W-W00	T8-9W-60-S-W-W00
T8-9W-60-ND-NW-W00	T8-9W-60-D-NW-W00	T8-9W-60-S-NW-W00
T8-9W-60-ND-WW-W00	T8-9W-60-D-WW-W00	T8-9W-60-S-WW-W00
T8-14W-90-ND-W-T00	T8-14W-90-D-W-T00	T8-14W-90-S-W-T00
T8-14W-90-ND-NW-T00	T8-14W-90-D-NW-T00	T8-14W-90-S-NW-T00
T8-14W-90-ND-WW-T00	T8-14W-90-D-WW-T00	T8-14W-90-S-WW-T00
T8-14W-90-ND-W-F00	T8-14W-90-D-W-F00	T8-14W-90-S-W-F00
T8-14W-90-ND-NW-F00	T8-14W-90-D-NW-F00	T8-14W-90-S-NW-F00
T8-14W-90-ND-WW-F00	T8-14W-90-D-WW-F00	T8-14W-90-S-WW-F00
T8-14W-90-ND-W-W00	T8-14W-90-D-W-W00	T8-14W-90-S-W-W00
T8-14W-90-ND-NW-W00	T8-14W-90-D-NW-W00	T8-14W-90-S-NW-W00
T8-14W-90-ND-WW-W00	T8-14W-90-D-WW-W00	T8-14W-90-S-WW-W00
T8-18W-120-ND-W-T00	T8-18W-120-D-W-T00	T8-18W-120-S-W-T00
T8-18W-120-ND-NW-T00	T8-18W-120-D-NW-T00	T8-18W-120-S-NW-T00
T8-18W-120-ND-WW-T00	T8-18W-120-D-WW-T00	T8-18W-120-S-WW-T00
T8-18W-120-ND-W-F00	T8-18W-120-D-W-F00	T8-18W-120-S-W-F00
T8-18W-120-ND-NW-F00	T8-18W-120-D-NW-F00	T8-18W-120-S-NW-F00
T8-18W-120-ND-WW-F00	T8-18W-120-D-WW-F00	T8-18W-120-S-WW-F00
T8-18W-120-ND-W-W00	T8-18W-120-D-W-W00	T8-18W-120-S-W-W00
T8-18W-120-ND-NW-W00	T8-18W-120-D-NW-W00	T8-18W-120-S-NW-W00
T8-18W-120-ND-WW-W00	T8-18W-120-D-WW-W00	T8-18W-120-S-WW-W00
T8-25W-150-ND-W-T00	T8-25W-150-D-W-T00	T8-25W-150-S-W-T00
T8-25W-150-ND-NW-T00	T8-25W-150-D-NW-T00	T8-25W-150-S-NW-T00
T8-25W-150-ND-WW-T00	T8-25W-150-D-WW-T00	T8-25W-150-S-WW-T00
T8-25W-150-ND-W-F00	T8-25W-150-D-W-F00	T8-25W-150-S-W-F00
T8-25W-150-ND-NW-F00	T8-25W-150-D-NW-F00	T8-25W-150-S-NW-F00
T8-25W-150-ND-WW-F00	T8-25W-150-D-WW-F00	T8-25W-150-S-WW-F00
T8-25W-150-ND-W-W00	T8-25W-150-D-W-W00	T8-25W-150-S-W-W00
T8-25W-150-ND-NW-W00	T8-25W-150-D-NW-W00	T8-25W-150-S-NW-W00
T8-25W-150-ND-WW-W00	T8-25W-150-D-WW-W00	T8-25W-150-S-WW-W00

SHENZHEN LCS COMPLIANCE TEST	TING LABORATORY LTD.	Report No.: LCS140225048E		
Belong to the tested of	levice:			
Product description Model name	: T8 LED Tube : T8-25W-150-ND-W-T	700		
Remark: PCB board, s So no addition	Remark: PCB board, structure and internal of these model(s) are the same, So no additional models were tested.			
	THE END OF REPORT-			